



S²MARTS Project No. 2010a: Electro-Optic Detector Characterization

Request For Solutions (RFS) Questions & Answers | Posted November 16th, 2020

1. **Question:** Should the measurements that support development of high-fidelity detector models be taken on raw detectors removed from the threat, or be taken while the detectors are still in the threat and include the effects of all mirrors, lenses, and coatings?

Response: Ideally, we may want measurements in both conditions. We definitely need to account for the effects of mirrors, lenses, and coatings in our models, but the basic project is to characterize only the detector response. It would be desirable if all detector measurements could be performed with the detectors *in situ*, but we are not sure if this is possible.

2. **Question:** Will the customer accept an RF solution?

Response: No, this is for EO/IR detectors only.